## Notice of References Cited Application/Control No. 10/579,239 Examiner Bradley K. Smith Applicant(s)/Patent Under Reexamination TANAKA ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

				0.0	
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2006/0091122	05-2006	Sugioka et al.	219/121.69
*	В	US-2002/0018288	02-2002	Rieger et al.	359/342
	O	US-			
	ם	US-			
	Е	US-			
	F	US-			
	O	US-			
	Ι	US-			
	_	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р		A			
	Q					
	R					
	s					
	I				1 C .	

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	WO 03/099508 Riken et al.
	V	
	w	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.